

PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Markus PROBST

Application No: 09/811,059

Filed: March 15, 2001

For: APPARATUS FOR MEASURING SCATTERED  
RADIATION

Art Unit: 2878

Examiner:  
Thanh X. Luu

FAX RECEIVED

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REPLY TO THE OFFICE ACTION MAILED 08/14/2002

TECHNOLOGY CENTER 2800

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

Further examination and consideration of this application are requested in view of the following Amendments and Remarks.

AMENDMENTSIn the Description:

Rewrite the title to read as follows:

APPARATUS FOR MEASURING SCATTERED RADIATION EMPLOYING AN  
EMITTING DEVICE OR A RECEIVING DEVICE THAT INCLUDES  
A DEFLECTION ELEMENT

Rewrite the paragraph beginning on page 1, line 29, to read as follows:

The object of the present invention is therefore to design an apparatus to measure scattered radiation in a more compact way.

Rewrite the paragraph beginning on page 4, line 1, to read as follows:

The representation shown in Figure 2 is repeated in Figure 3 in a view from the fluid side 5. One can see an approximately circular separating pane 4 behind which the first and second reflecting prisms 8, 9 are located, as are the light source 1 and the detector 2. Even though this apparatus is much more compact than the prior-art